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(54) Title: INTERLEAVING METHOD FOR LOW DENSITY PARITY CHECK ENCODING

(57) Abstract: The present invention relates to an interleaving method for achieving a high error correction rate when burst errors are generated in an encoding process using a low density parity check (LDPC). The method comprises: generating more than one code word vector by generating parity information on the basis of a parity check matrix; dividing the generated code word vector into interleaving units, each having the size determined on the basis of bit lengths between 1s included in a row of the parity check matrix; and interleaving the more than one code word vector using the interleaving unit. Accordingly, reliability of error correction increases by determining the size of an optimum interleaving unit when an LDPC encoding process is performed.

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